

N-Channel Enhancement Mode MOSFET

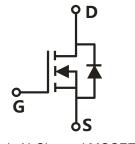
Feature

- 30V/375A $R_{DS(ON)}= 0.55 \text{ m}\Omega(\text{typ.}) \text{ @VGS} = 10V$ $R_{DS(ON)}= 0.80 \text{ m}\Omega(\text{typ.}) \text{ @VGS} = 4.5V$
- 100% Avalanche Tested
- 100% DVDS
- Reliable and Rugged
- Halogen Free and Green Devices Available (RoHS Compliant)

Applications

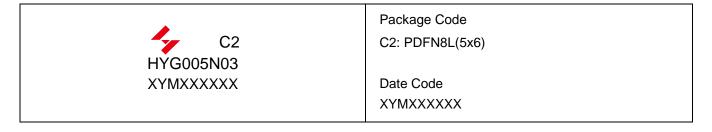
- Load Switch
- Battery Protection

Pin Description



Single N-Channel MOSFET

Ordering and Marking Information



Note: HUAYI halogen free products contain molding compounds/die attach materials and 100% matte tin plate Termi-Nation finish; which are fully compliant with RoHS. HUAYI halogen free products meet or exceed the halogen free require-ments of IPC/JEDEC J-STD-020 for MSL classification at halogen free peak reflow temperature. HUAYI defines "Green" to mean halogen free (RoHS compliant) and halogen free (Br or Cl does not exceed 900ppm by weight in homogeneous material and total of Br and Cl does not exceed 1500ppm by weight).

HUAYI reserves the right to make changes, corrections, enhancements, modifications, and improvements to this pr-oduct and/or to this document at any time without notice.



Absolute Maximum Ratings

Symbol	Parameter	Rating	Unit			
Common Rat	Common Ratings (Tc=25°C Unless Otherwise Noted)					
VDSS	Drain-Source Voltage		30	V		
Vgss	Gate-Source Voltage		±20	V		
TJ	Junction Temperature Range		55 1. 475	°C		
Tstg	Storage Temperature Range		-55 to 175	°C		
Is	Source Current-Continuous(Body Diode) Tc=25°C		375	А		
Mounted on I	Mounted on Large Heat Sink					
Ідм	Pulsed Drain Current *	Tc=25°C	1350	А		
			375	А		
lσ	Continuous Drain Current	Tc=100°C	265	А		
1	Martin or Broad Pirate of the	Tc=25°C	230	W		
Po	Maximum Power Dissipation Tc=100°C		115	W		
R₀JC	Thermal Resistance, Junction-to-Case		0.65	°C/W		
R _{eJA}	Thermal Resistance, Junction-to-Ambient **		80	°C/W		
Eas	Single Pulsed-Avalanche Energy *** L=0.3mH		1960	mJ		

Note:

- * Repetitive rating; pulse width limited by max.junction temperature.
- ** Surface mounted on 1in2 FR-4 board.
- *** Limited by TJmax , starting TJ=25°C, L = 0.3mH, Rg= 25Ω , Vgs =10V.

Electrical Characteristics(Tc =25°C Unless Otherwise Noted)

Cumbal	Parameter	Test Conditions		HYG005N03LR1			11:0:4
Symbol	Parameter			Min	Тур.	Max	Unit
Static Cha	Static Characteristics						
BVDSS	Drain-Source Breakdown Voltage	$V_{GS}=0V,I_{DS}=250\mu A$		30	-	-	V
Ipss	Drain-to-Source Leakage Current	VDS=30V,VGS	VDS=30V,VGS=0V		-	1	μΑ
IDSS			TJ=125°C	-	-	50	μΑ
VGS(th)	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250µA		1	1.8	3	V
Igss	Gate-Source Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$		-	-	±100	nA
Process	RDS(ON) Drain-Source On-State Resistance		=20A	-	0.55	0.9	$m\Omega$
KDS(ON)			=20A	-	0.80	1.1	mΩ
Diode Cha	Diode Characteristics						
VsD	Diode Forward Voltage	IsD=20A,VGS=0V		-	0.75	1.0	V
trr	Reverse Recovery Time	Isb=20A,dIsb/dt=100A/μs		-	37	-	ns
Qrr	Reverse Recovery Charge			-	38	-	nC



Electrical Characteristics (Cont.) (Tc =25°C Unless Otherwise Noted)

Or made at		T	HY	HYG005N03LR1		
Symbol	Parameter Test Conditions		Min	Тур.	Max	Unit
Dynamic	Characteristics					
Rg	Gate Resistance	V _{GS} =0V,V _{DS} =0V,F=500KHz	-	1.2	-	Ω
Ciss	Input Capacitance	V _G s=0V,	-	8718	-	
Coss	Output Capacitance	V _{DS} =25V,	-	1330	-	pF
Crss	Reverse Transfer Capacitance	Frequency=500KHz	-	1050	-	
td(ON)	Turn-on Delay Time		-	18	-	
Tr	Turn-on Rise Time	VDD=15V,RG=4 Ω ,	-	58	-	
td(OFF)	Turn-off Delay Time	lps=20A,Vgs=10V	-	118	-	ns
Tf	Turn-off Fall Time		-	91	-	
Gate Cha	rge Characteristics					
Qg	Total Gate Charge(V _{GS} =10V)		-	203	-	
Qg	Total Gate Charge(V _{GS} =4.5V)		-	109	-	" C
Qgs	Gate-Source Charge	V _{DS} =24V, I _{DS} =20A	-	27	-	nC
Qgd	Gate-Drain Charge		-	56	-	
V _{plateau}	Gate plateau voltage		-	3	-	V

Note: *Pulse test, pulse width ≤ 300us, duty cycle ≤ 2%



Typical Operating Characteristics

Figure 1: Power Dissipation

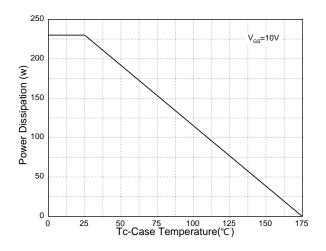


Figure 3: Safe Operation Area

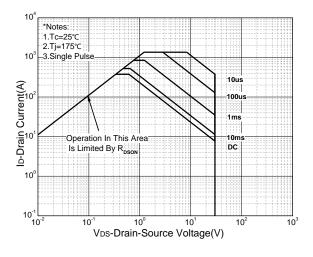


Figure 5: Output Characteristics

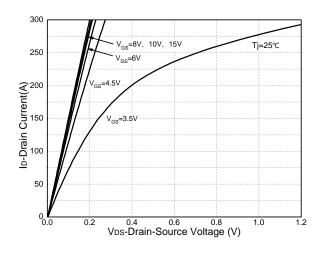


Figure 2: Drain Current

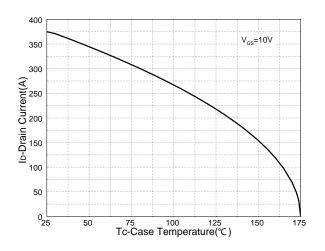
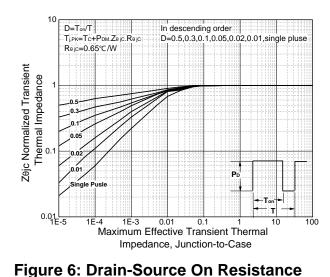
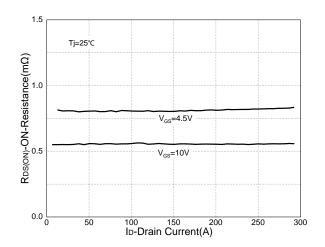


Figure 4: Thermal Transient Impedance







Typical Operating Characteristics(Cont.)

Figure 7: On-Resistance vs. Temperature

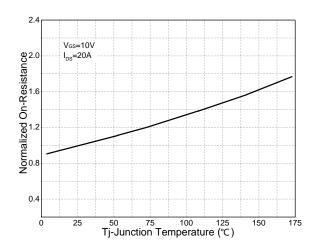


Figure 8: Source-Drain Diode Forward

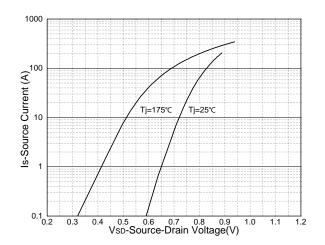


Figure 9: Capacitance Characteristics

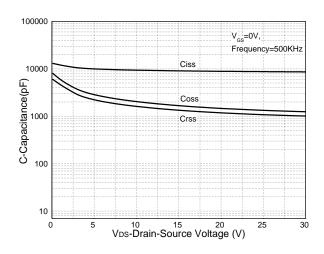
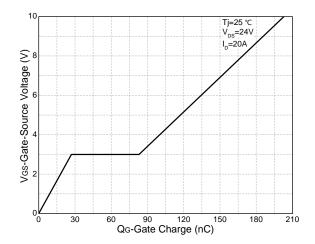
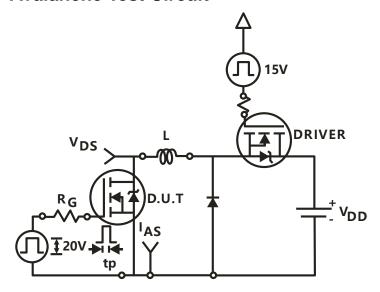


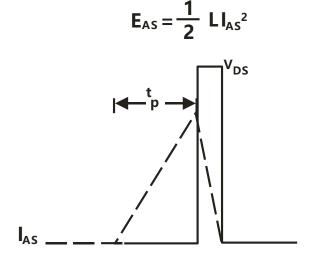
Figure 10: Gate Charge Characteristics



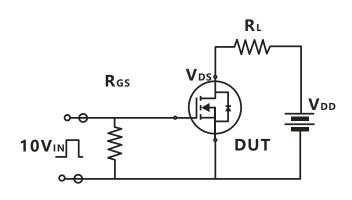


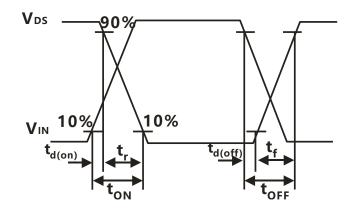
Avalanche Test Circuit



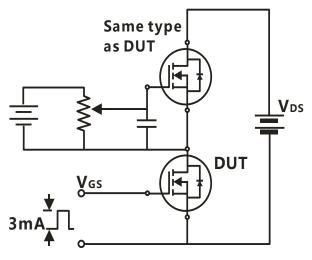


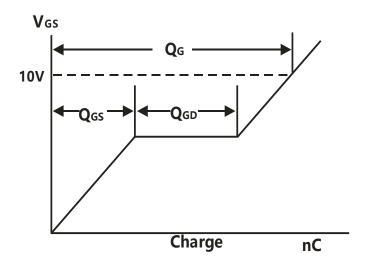
Switching Time Test Circuit





Gate Charge Test Circuit







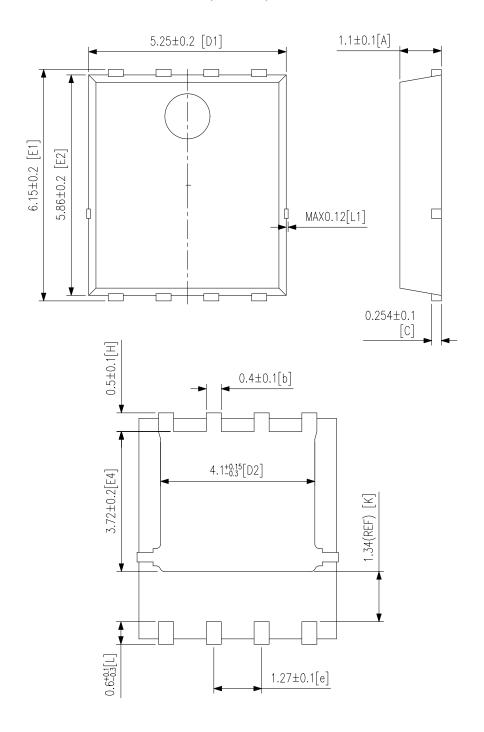
Device Per Unit

Package Type	Unit	Quantity
PDFN8L(5x6)	Reel	5000

Package Information

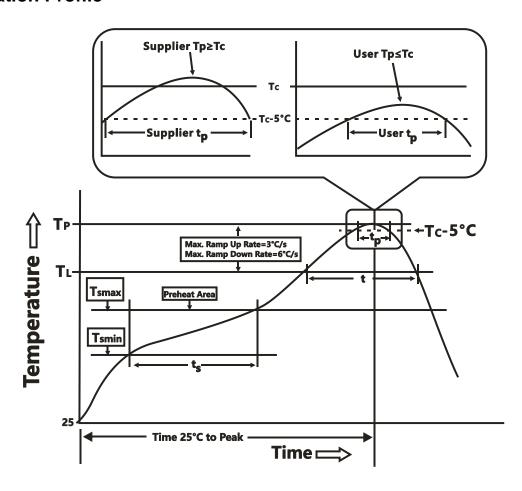
PDFN8L(5x6)

(unit:mm)





Classification Profile



Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly			
Preheat & Soak					
Temperature min (T _{smin})	100 °C	150 °C			
Temperature max (T _{smax})	150 °C	200 °C			
Time (Tsmin to Tsmax) (t _s)	60-120 seconds	60-120 seconds			
Average ramp-up rate	2 °C/second may	2°C/cocond may			
(T _{smax} to T _P)	3 °C/second max.	3°C/second max.			
Liquidous temperature (T _L)	183 °C	217 °C			
Time at liquidous (t _L)	60-150 seconds	60-150 seconds			
Peak package body Temperature	See Classification Temp in table 1	SeeClassification Tempin table 2			
(T _p)*	See Classification Temp in table 1				
Time (t _P)** within 5°C of the specified	20** accords	20** accords			
classification temperature (T _c)	20** seconds	30** seconds			
Average ramp-down rate (Tpto Tsmax)	6 °C/second max.	6 °C/second max.			
Time 25°C to peak temperature	6 minutes max.	8 minutes max.			

^{*}Tolerance for peak profile Temperature (Tp) is defined as a supplier minimum and a user maximum.

^{**} Tolerance for time at peak profile temperature (t_p) is defined as a supplier minimum and a user maximum.

HYG005N03LR1C2



Table 1.SnPb Eutectic Process – Classification Temperatures (Tc)

Package Thickness	Volume mm³ <350	Volume mm³ ≥350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2.Pb-free Process – Classification Temperatures (Tc)

Package	Volume mm ³	Volume mm ³	Volume mm³
Thickness	<350	350-2000	≥2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

Reliability Test Program

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C
HTRB	JESD-22, A108	168/500/1000 Hrs, Bias @ 150°C
HTGB	JESD-22, A108	168 /500/1000 Hrs, Vgs100% @ 150°C
PCT	JESD-22, A102	96 Hrs, 100%RH, 2atm, 121°C
ТСТ	JESD-22, A104	250/500/1000 Cycles, -55°C~150°C

Customer Service

Worldwide Sales and Service: sales@hymexa.com Technical Support:Technology@hymexa.com

Huayi Microelectronics Co., Ltd.

No.8928, Shangji Road, Economic and Technological Development Zone, Xi'an, China

TEL: (86-029) 86685706 FAX: (86-029) 86685705 E-mail: sales@hymexa.com Web net: http://www.hymexa.com/